

501.43127X00

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s): C. SHISHIDO, et al

Serial No.: (not yet assigned)

Filed: October 7, 2003

For: A METHOD FOR MEASURING THREE-DIMENSIONAL SHAPE  
OF A FINE PATTERN

**PRELIMINARY AMENDMENT**

Mail Stop Non-Fee Amendment

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

October 7, 2003

Sir:

The following amendments and remarks are respectfully submitted in connection with the above-identified application, as listed below and as set forth on the following pages:

Marked Up Specification and Substitute Specification;

Amendments to the Abstract;

Amendments to the Claims; and

Remarks are included following the amendments.